

Abstracts

X-Band Burnout Characteristics of GaAs MESFETs (1982 [MWSYM])

J.J. Whalen and R.T. Kemerley. "X-Band Burnout Characteristics of GaAs MESFETs (1982 [MWSYM])." 1982 MTT-S International Microwave Symposium Digest 82.1 (1982 [MWSYM]): 286-288.

X-Band microsecond pulse, millisecond pulse, and CW burnout data have been measured for GaAs MESFETs. Values of incident pulse power required to cause burn-out are presented and discussed.

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